

Re: Schlieren Microscopes

Source: <http://sci.tech-archive.net/Archive/sci.techniques.microscopy/2005-11/msg00083.html>

- *From:* hbarwood@xxxxxxxx
 - *Date:* 21 Nov 2005 16:27:24 -0800
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Hi Rene,

I am intrigued by the potential of the method to detect subtle variations in refractive index/dispersion. I work with petrographic thin sections and would like to look for compositional gradients in minerals. There are lots of techniques to do this, but I am always on the lookout for something new.

Henry

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